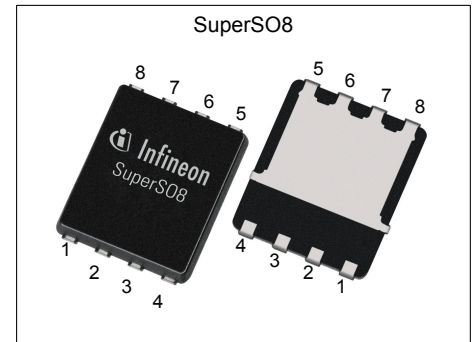


# MOSFET

## OptiMOS™ Power-Transistor, 60 V

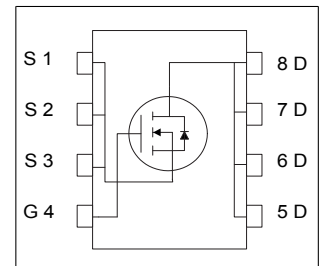
### Features

- Optimized for high performance SMPS, e.g. sync. rec.
- 175 °C rated
- 100% avalanche tested
- Superior thermal resistance
- N-channel
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21



**Table 1 Key Performance Parameters**

| Parameter        | Value | Unit |
|------------------|-------|------|
| $V_{DS}$         | 60    | V    |
| $R_{DS(on),max}$ | 9.7   | mΩ   |
| $I_D$            | 48    | A    |
| $Q_{OSS}$        | 14    | nC   |
| $Q_G(0V..10V)$   | 12    | nC   |



| Type / Ordering Code | Package    | Marking  | Related Links |
|----------------------|------------|----------|---------------|
| BSC097N06NST         | PG-TDSON-8 | 097N06NT | -             |

<sup>1)</sup> J-STD20 and JESD22

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## 1 Maximum ratings

at  $T_A=25\text{ °C}$ , unless otherwise specified

**Table 2 Maximum ratings**

| Parameter                                     | Symbol            | Values |      |                | Unit | Note / Test Condition                                                                                                                                                |
|-----------------------------------------------|-------------------|--------|------|----------------|------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------|
|                                               |                   | Min.   | Typ. | Max.           |      |                                                                                                                                                                      |
| Continuous drain current                      | $I_D$             | -      | -    | 48<br>34<br>13 | A    | $V_{GS}=10\text{ V}$ , $T_C=25\text{ °C}$<br>$V_{GS}=10\text{ V}$ , $T_C=100\text{ °C}$<br>$V_{GS}=10\text{ V}$ , $T_A=25\text{ °C}$ , $R_{thJA}=50\text{K/W}^{(1)}$ |
| Pulsed drain current <sup>(2)</sup>           | $I_{D,pulse}$     | -      | -    | 192            | A    | $T_C=25\text{ °C}$                                                                                                                                                   |
| Avalanche energy, single pulse <sup>(3)</sup> | $E_{AS}$          | -      | -    | 13             | mJ   | $I_D=30\text{ A}$ , $R_{GS}=25\text{ }\Omega$                                                                                                                        |
| Gate source voltage                           | $V_{GS}$          | -20    | -    | 20             | V    | -                                                                                                                                                                    |
| Power dissipation                             | $P_{tot}$         | -      | -    | 43<br>3.0      | W    | $T_C=25\text{ °C}$<br>$T_A=25\text{ °C}$ , $R_{thJA}=50\text{ K/W}^{(1)}$                                                                                            |
| Operating and storage temperature             | $T_j$ , $T_{stg}$ | -55    | -    | 175            | °C   | -                                                                                                                                                                    |

## 2 Thermal characteristics

**Table 3 Thermal characteristics**

| Parameter                                                    | Symbol     | Values |      |      | Unit | Note / Test Condition |
|--------------------------------------------------------------|------------|--------|------|------|------|-----------------------|
|                                                              |            | Min.   | Typ. | Max. |      |                       |
| Thermal resistance, junction - case, bottom                  | $R_{thJC}$ | -      | 2.1  | 3.5  | K/W  | -                     |
| Thermal resistance, junction - case, top                     | $R_{thJC}$ | -      | -    | 20   | K/W  | -                     |
| Device on PCB, 6 cm <sup>2</sup> cooling area <sup>(1)</sup> | $R_{thJA}$ | -      | -    | 50   | K/W  | -                     |

<sup>(1)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

<sup>(2)</sup> See Diagram 3 for more detailed information

<sup>(3)</sup> See Diagram 13 for more detailed information

### 3 Electrical characteristics

**Table 4 Static characteristics**

| Parameter                        | Symbol        | Values |             |             | Unit          | Note / Test Condition                                                                                                                                       |
|----------------------------------|---------------|--------|-------------|-------------|---------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------|
|                                  |               | Min.   | Typ.        | Max.        |               |                                                                                                                                                             |
| Drain-source breakdown voltage   | $V_{(BR)DSS}$ | 60     | -           | -           | V             | $V_{GS}=0\text{ V}$ , $I_D=1\text{ mA}$                                                                                                                     |
| Gate threshold voltage           | $V_{GS(th)}$  | 2.1    | 2.8         | 3.3         | V             | $V_{DS}=V_{GS}$ , $I_D=14\text{ }\mu\text{A}$                                                                                                               |
| Zero gate voltage drain current  | $I_{DSS}$     | -      | 0.1<br>10   | 1<br>100    | $\mu\text{A}$ | $V_{DS}=60\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=25\text{ }^\circ\text{C}$<br>$V_{DS}=60\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=125\text{ }^\circ\text{C}$ |
| Gate-source leakage current      | $I_{GSS}$     | -      | 10          | 100         | nA            | $V_{GS}=20\text{ V}$ , $V_{DS}=0\text{ V}$                                                                                                                  |
| Drain-source on-state resistance | $R_{DS(on)}$  | -      | 8.0<br>12.0 | 9.7<br>14.6 | m $\Omega$    | $V_{GS}=10\text{ V}$ , $I_D=40\text{ A}$<br>$V_{GS}=6\text{ V}$ , $I_D=10\text{ A}$                                                                         |
| Gate resistance <sup>1)</sup>    | $R_G$         | -      | 1.1         | 1.7         | $\Omega$      | -                                                                                                                                                           |
| Transconductance                 | $g_{fs}$      | 24     | 48          | -           | S             | $ V_{DS} >2 I_D R_{DS(on)max}$ , $I_D=40\text{ A}$                                                                                                          |

**Table 5 Dynamic characteristics<sup>1)</sup>**

| Parameter                    | Symbol       | Values |      |      | Unit | Note / Test Condition                                                                                  |
|------------------------------|--------------|--------|------|------|------|--------------------------------------------------------------------------------------------------------|
|                              |              | Min.   | Typ. | Max. |      |                                                                                                        |
| Input capacitance            | $C_{iss}$    | -      | 860  | 1075 | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=30\text{ V}$ , $f=1\text{ MHz}$                                          |
| Output capacitance           | $C_{oss}$    | -      | 210  | 263  | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=30\text{ V}$ , $f=1\text{ MHz}$                                          |
| Reverse transfer capacitance | $C_{rss}$    | -      | 16   | 32   | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=30\text{ V}$ , $f=1\text{ MHz}$                                          |
| Turn-on delay time           | $t_{d(on)}$  | -      | 6    | -    | ns   | $V_{DD}=30\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=40\text{ A}$ ,<br>$R_{G,ext,ext}=1.6\text{ }\Omega$ |
| Rise time                    | $t_r$        | -      | 2    | -    | ns   | $V_{DD}=30\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=40\text{ A}$ ,<br>$R_{G,ext,ext}=1.6\text{ }\Omega$ |
| Turn-off delay time          | $t_{d(off)}$ | -      | 10   | -    | ns   | $V_{DD}=30\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=40\text{ A}$ ,<br>$R_{G,ext,ext}=1.6\text{ }\Omega$ |
| Fall time                    | $t_f$        | -      | 2    | -    | ns   | $V_{DD}=30\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=40\text{ A}$ ,<br>$R_{G,ext,ext}=1.6\text{ }\Omega$ |

**Table 6 Gate charge characteristics<sup>2)</sup>**

| Parameter                    | Symbol        | Values |      |      | Unit | Note / Test Condition                                                       |
|------------------------------|---------------|--------|------|------|------|-----------------------------------------------------------------------------|
|                              |               | Min.   | Typ. | Max. |      |                                                                             |
| Gate to source charge        | $Q_{gs}$      | -      | 4.5  | -    | nC   | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate charge at threshold     | $Q_{g(th)}$   | -      | 2.4  | -    | nC   | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate to drain charge         | $Q_{gd}$      | -      | 2.6  | 3.7  | nC   | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Switching charge             | $Q_{sw}$      | -      | 4.7  | -    | nC   | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate charge total            | $Q_g$         | -      | 12   | 15   | nC   | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate plateau voltage         | $V_{plateau}$ | -      | 5.2  | -    | V    | $V_{DD}=30\text{ V}$ , $I_D=40\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate charge total, sync. FET | $Q_{g(sync)}$ | -      | 10   | -    | nC   | $V_{DS}=0.1\text{ V}$ , $V_{GS}=0\text{ to }10\text{ V}$                    |
| Output charge                | $Q_{oss}$     | -      | 14   | 19   | nC   | $V_{DD}=30\text{ V}$ , $V_{GS}=0\text{ V}$                                  |

<sup>1)</sup> Defined by design. Not subject to production test

<sup>2)</sup> Defined by design. Not subject to production test. See, Gate charge waveforms, for gate charge parameter definition

**Table 7 Reverse diode**

| Parameter                             | Symbol        | Values |      |      | Unit | Note / Test Condition                                                      |
|---------------------------------------|---------------|--------|------|------|------|----------------------------------------------------------------------------|
|                                       |               | Min.   | Typ. | Max. |      |                                                                            |
| Diode continuous forward current      | $I_S$         | -      | -    | 36   | A    | $T_C=25\text{ °C}$                                                         |
| Diode pulse current                   | $I_{S,pulse}$ | -      | -    | 192  | A    | $T_C=25\text{ °C}$                                                         |
| Diode forward voltage                 | $V_{SD}$      | -      | 1.0  | 1.2  | V    | $V_{GS}=0\text{ V}$ , $I_F=30\text{ A}$ , $T_j=25\text{ °C}$               |
| Reverse recovery time <sup>1)</sup>   | $t_{rr}$      | -      | 33   | 53   | ns   | $V_R=30\text{ V}$ , $I_F=30\text{ A}$ , $di_F/dt=100\text{ A/}\mu\text{s}$ |
| Reverse recovery charge <sup>1)</sup> | $Q_{rr}$      | -      | 30   | -    | nC   | $V_R=30\text{ V}$ , $I_F=30\text{ A}$ , $di_F/dt=100\text{ A/}\mu\text{s}$ |

<sup>1)</sup> Defined by design. Not subject to production test

## 4 Electrical characteristics diagrams

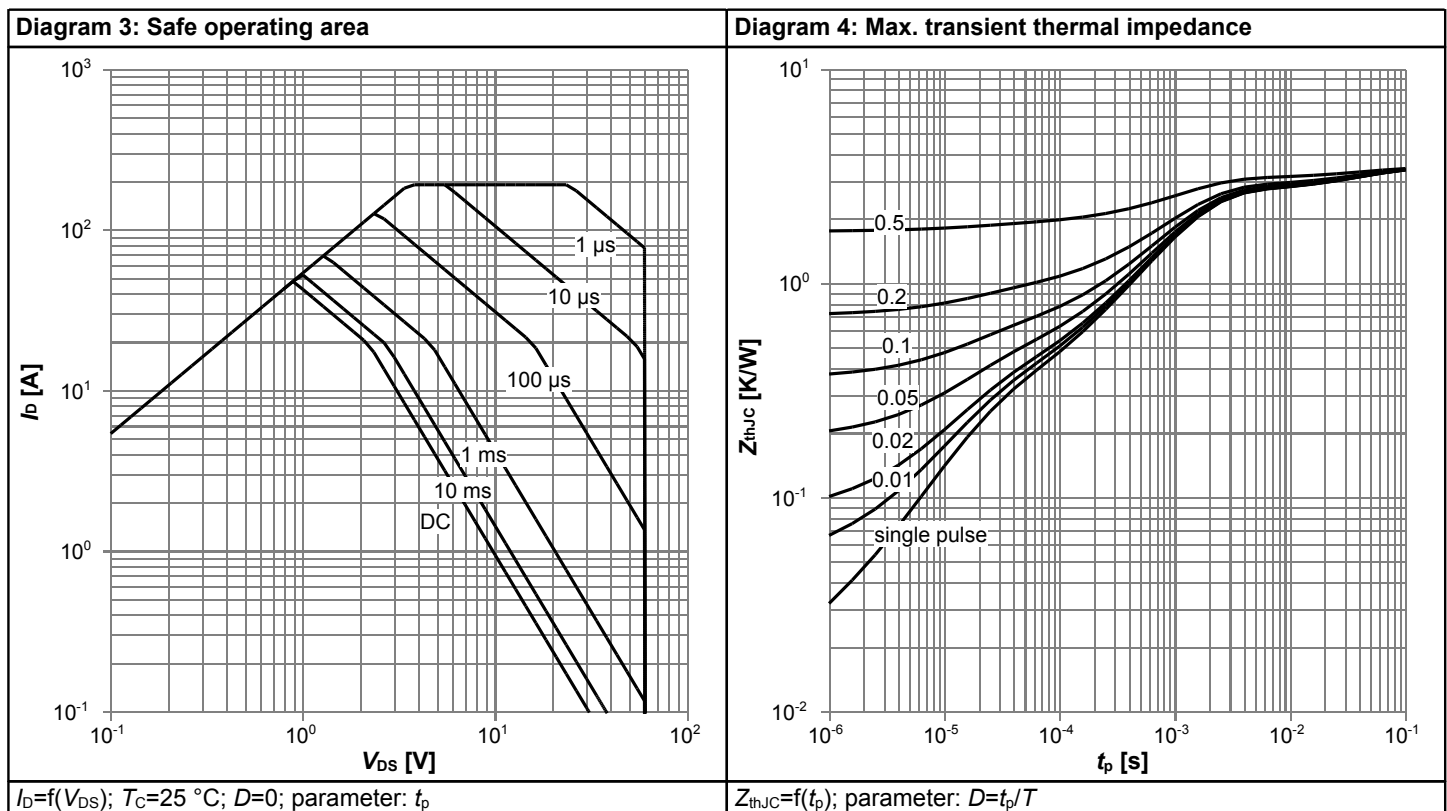
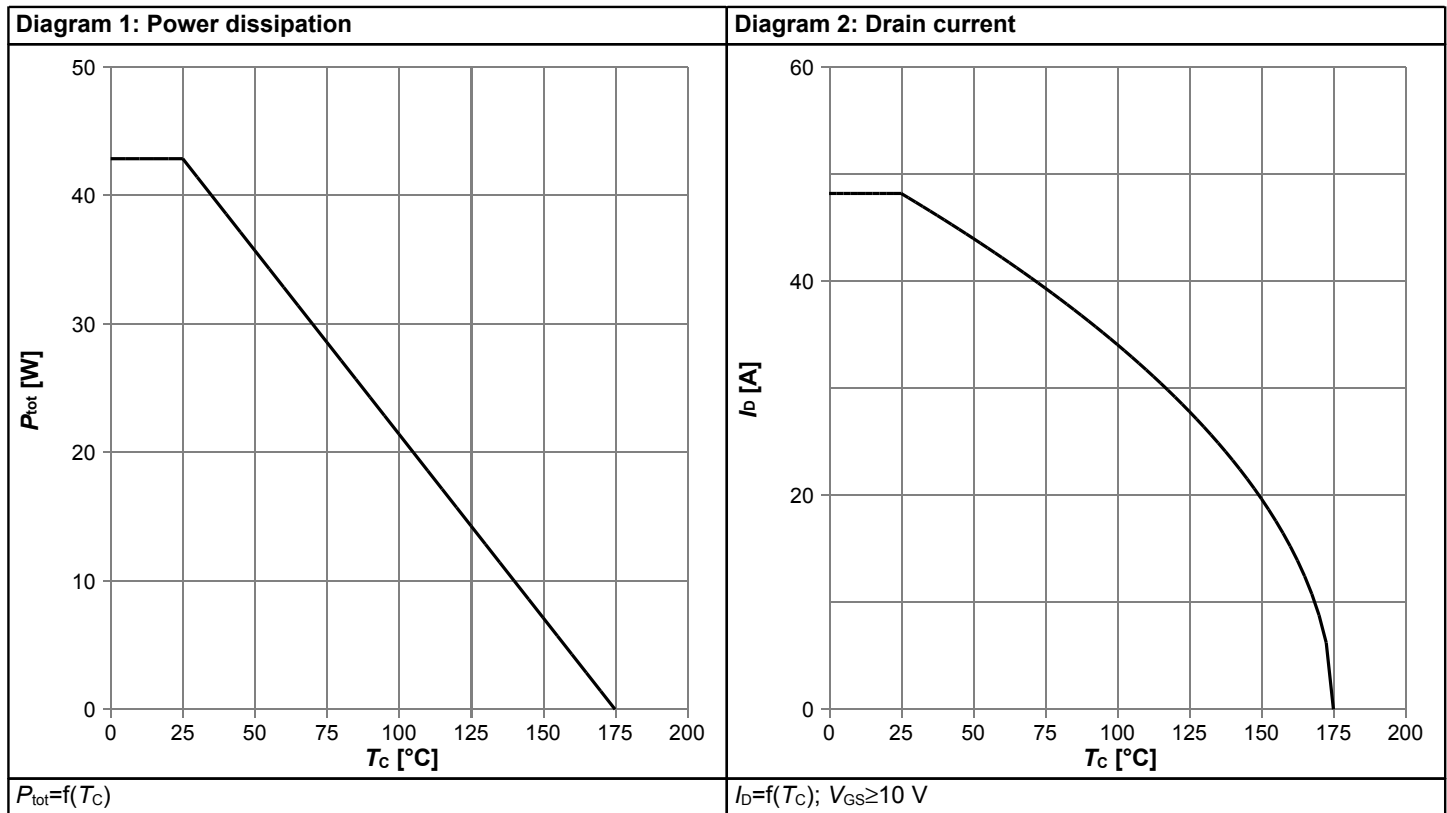
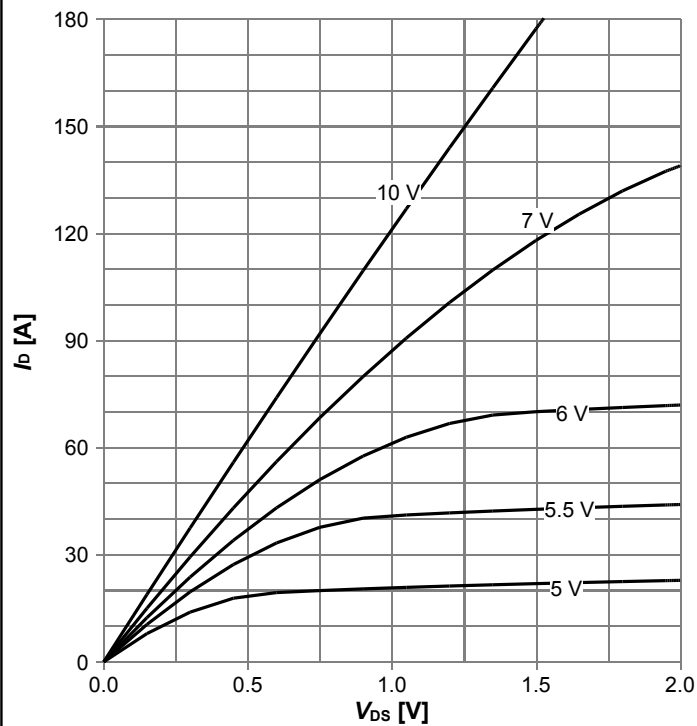
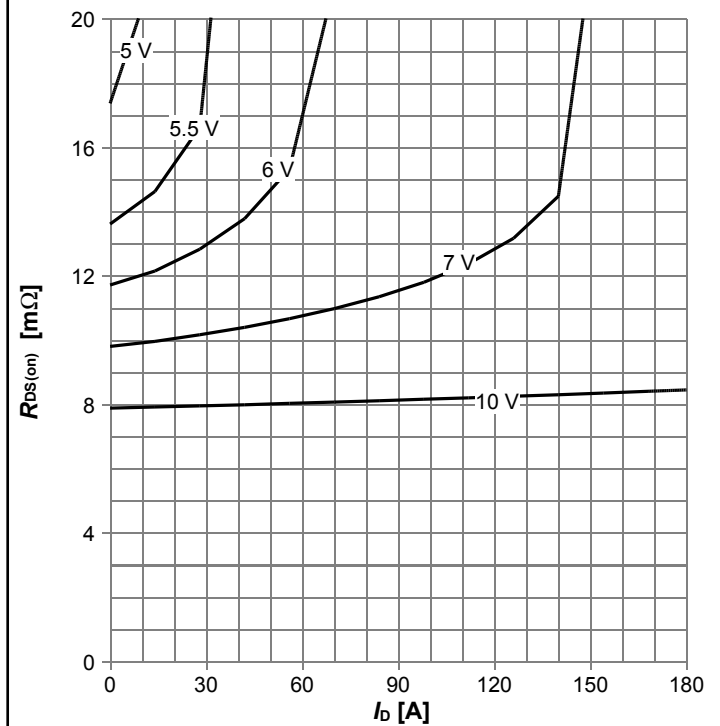


Diagram 5: Typ. output characteristics



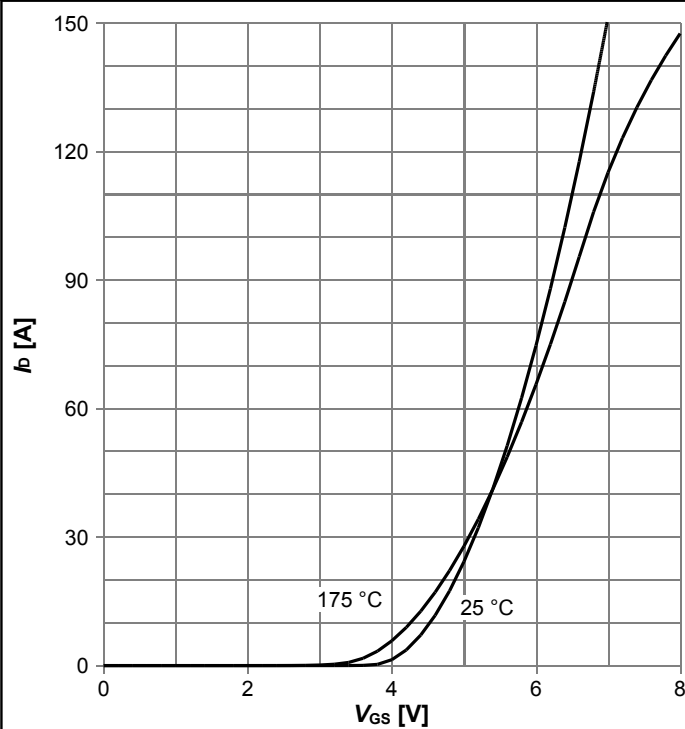
$I_D = f(V_{DS})$ ;  $T_j = 25^\circ\text{C}$ ; parameter:  $V_{GS}$

Diagram 6: Typ. drain-source on resistance



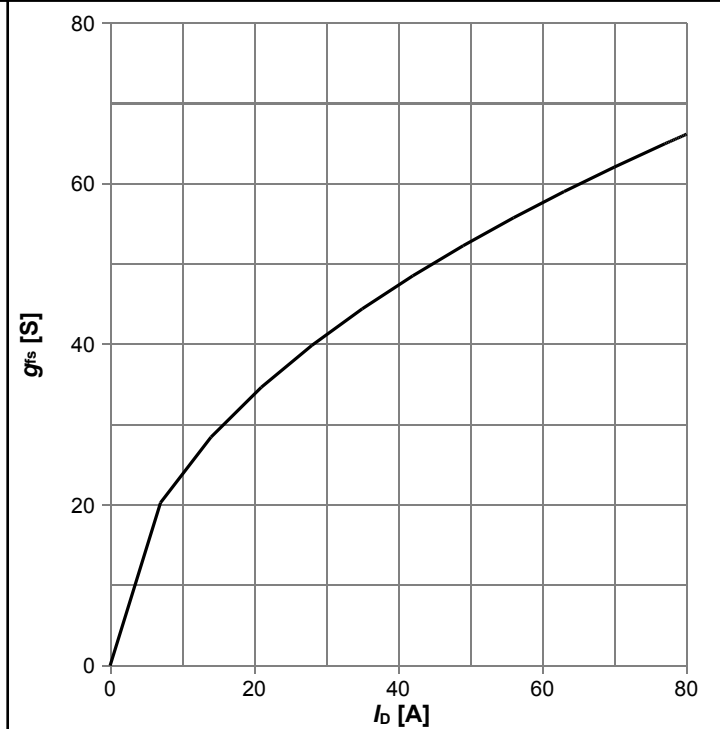
$R_{DS(on)} = f(I_D)$ ;  $T_j = 25^\circ\text{C}$ ; parameter:  $V_{GS}$

Diagram 7: Typ. transfer characteristics



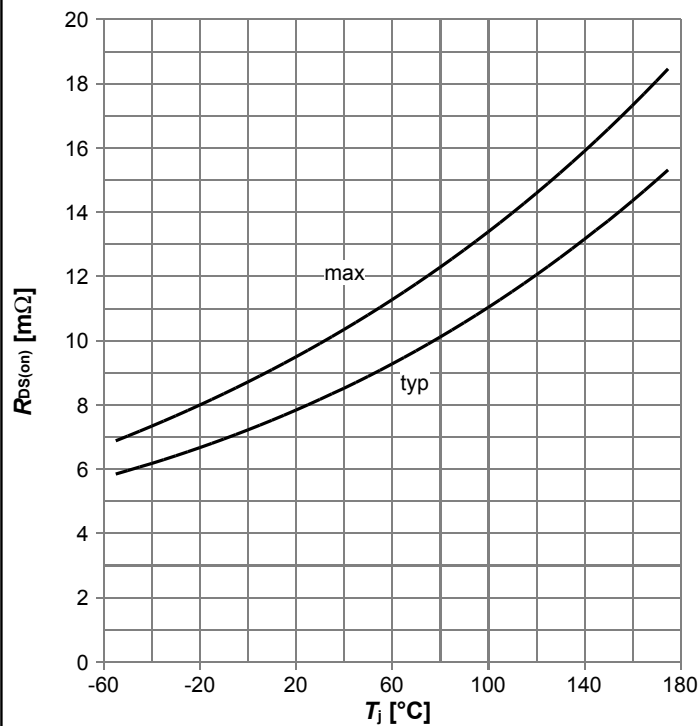
$I_D = f(V_{GS})$ ;  $|V_{DS}| > 2|I_D|R_{DS(on)max}$ ; parameter:  $T_j$

Diagram 8: Typ. forward transconductance



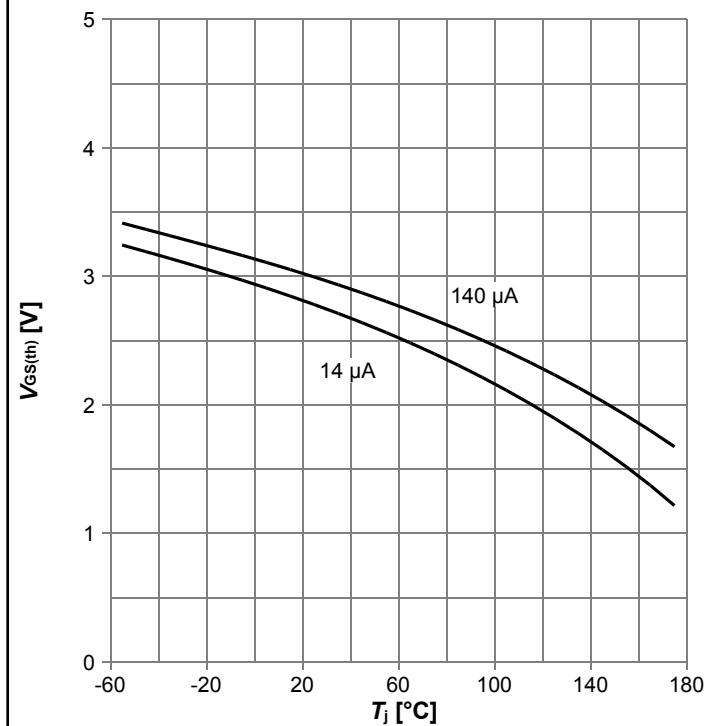
$g_{fs} = f(I_D)$ ;  $T_j = 25^\circ\text{C}$

Diagram 9: Drain-source on-state resistance



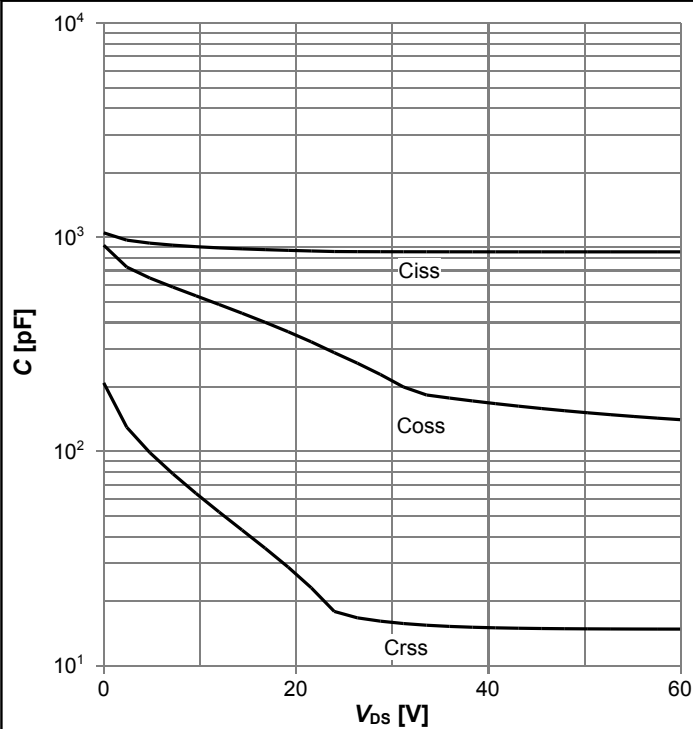
$R_{DS(on)} = f(T_j)$ ;  $I_D = 40$  A;  $V_{GS} = 10$  V

Diagram 10: Typ. gate threshold voltage



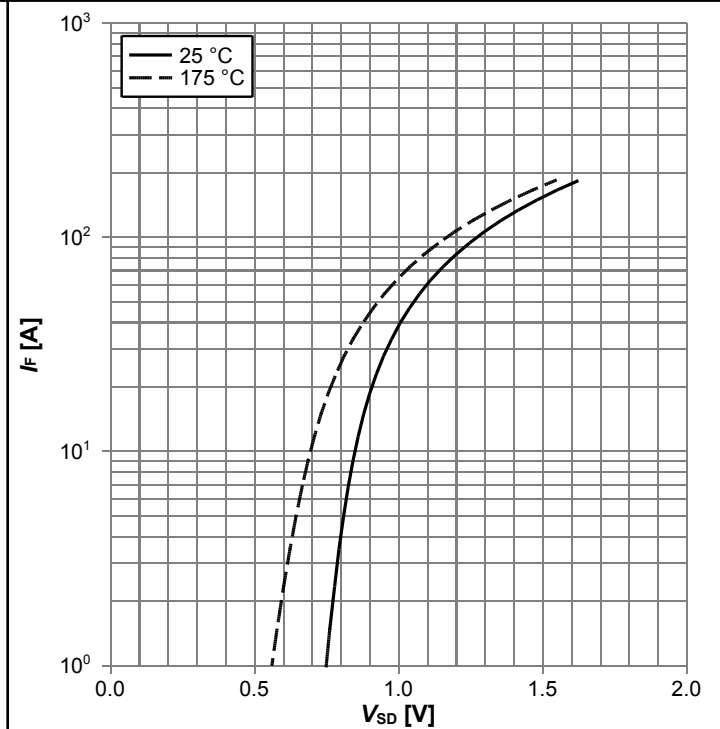
$V_{GS(th)} = f(T_j)$ ;  $V_{GS} = V_{DS}$

Diagram 11: Typ. capacitances



$C = f(V_{DS})$ ;  $V_{GS} = 0$  V;  $f = 1$  MHz

Diagram 12: Forward characteristics of reverse diode



$I_F = f(V_{SD})$ ; parameter:  $T_j$



Diagram 13: Avalanche characteristics

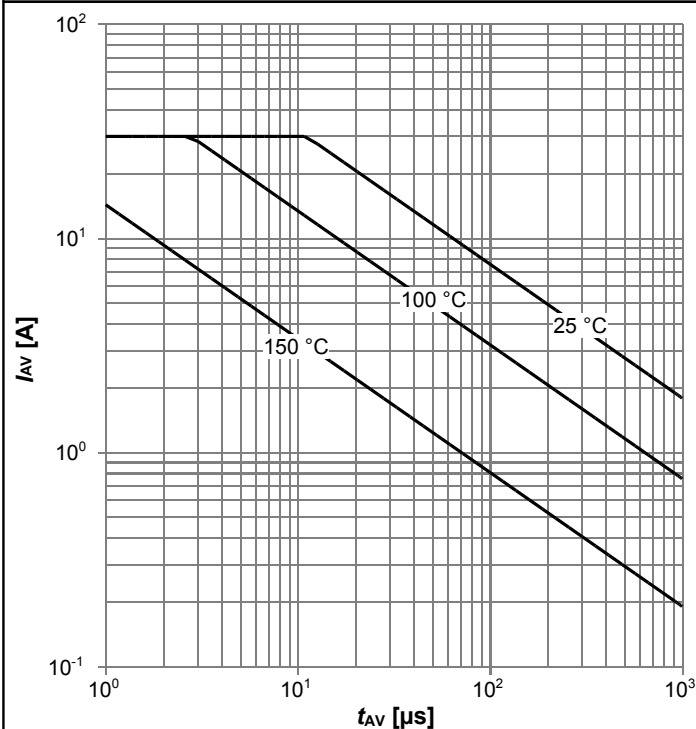


Diagram 14: Typ. gate charge

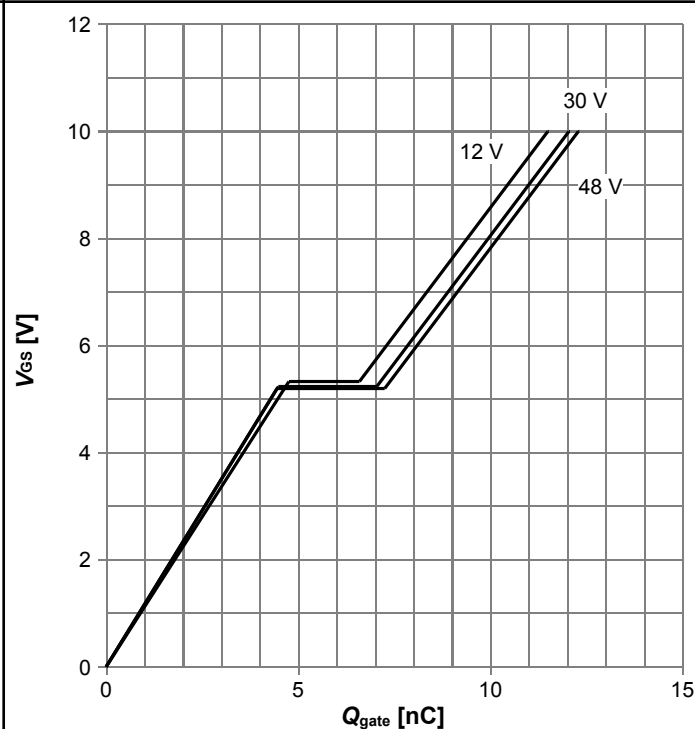
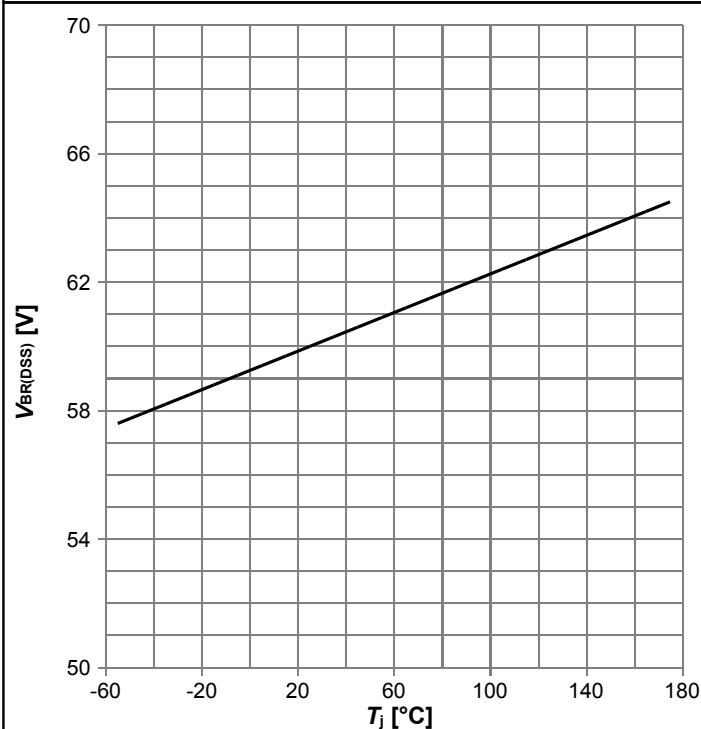
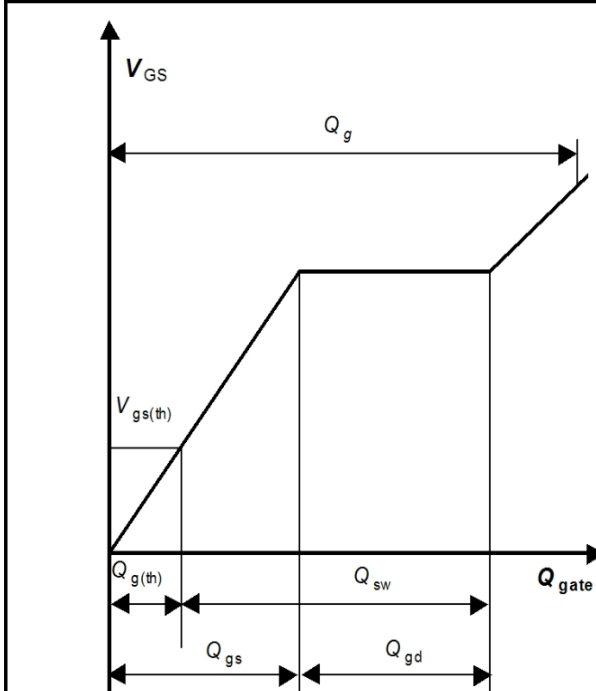


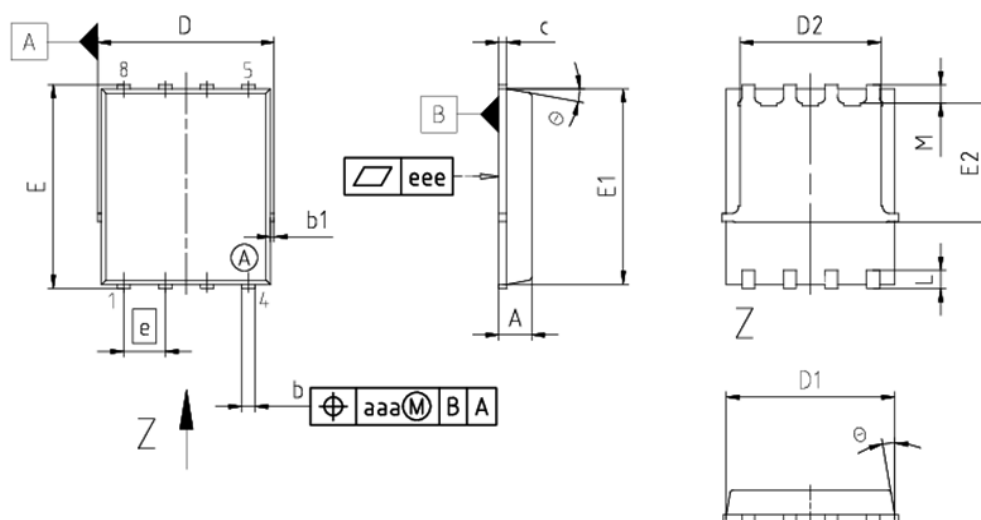
Diagram 15: Drain-source breakdown voltage



Gate charge waveforms



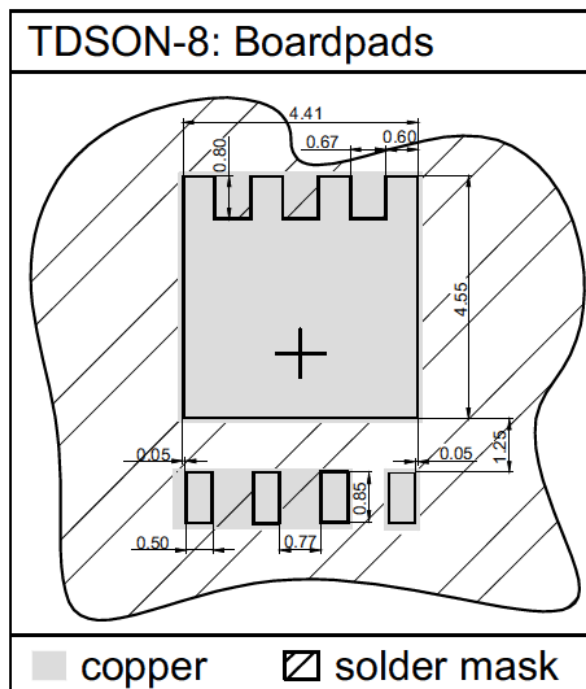
## 5 Package Outlines



| DIM   | MILLIMETERS |      |
|-------|-------------|------|
|       | MIN         | MAX  |
| A     | 0.90        | 1.10 |
| b     | 0.31        | 0.54 |
| b1    | 0.02        | 0.22 |
| c     | 0.15        | 0.35 |
| D     | 5.15        | 5.49 |
| D1    | 4.95        | 5.35 |
| D2    | 3.70        | 4.40 |
| E     | 5.95        | 6.35 |
| E1    | 5.70        | 6.10 |
| E2    | 3.40        | 3.80 |
| e     | 1.27        |      |
| N     | 8           |      |
| L     | 0.45        | 0.71 |
| M     | 0.45        | 0.75 |
| theta | 8.5°        | 12°  |
| aaa   | 0.25        |      |
| eee   | 0.08        |      |

|                             |
|-----------------------------|
| DOCUMENT NO.<br>Z8B00003332 |
| SCALE<br>0 2 4mm            |
| EUROPEAN PROJECTION<br>     |
| ISSUE DATE<br>10-04-2013    |
| REVISION<br>04              |

Figure 1 Outline PG-TDSON-8, dimensions in mm



**Figure 2 Outline Footprint (TDSO-8)**

## Revision History

BSC097N06NST

**Revision: 2017-10-19, Rev. 2.0**

Previous Revision

| Revision | Date       | Subjects (major changes since last revision) |
|----------|------------|----------------------------------------------|
| 2.0      | 2017-10-19 | Release of final version                     |

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